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Higher performance on HESI Exit Exams is associated with increased likelihood of success on the Next Generation NCLEX-PN®

A recent study investigated the relationship between performance on the HESI Exit Exam (E2) and NCLEX-PN (NGN-PN) success, as well as the impact of program policies on attaining exit exam benchmarks.

Study details:

- **Sample size:** 404 students from 9 nursing programs
- **Exam window:** 2023-2024
- **Policy data:** Collected from 10 programs
- Examined first, last, average, and highest E2 scores for each student

Key findings

In our sample, students with higher E2 scores were more likely to pass the NGN-PN on the first attempt. The overall first-time pass rate was 93.6%. On average, students' last E2 score was 888.5, and their overall average E2 score was 874.0.

Students were significantly more likely to pass the NGN-PN on their first attempt if they attained benchmark scores of either 850 or 900 on the E2. Specifically:

- Students' average E2 scores were 188.4 points higher among those who passed the NGN-PN, compared to those who failed
- Students' last E2 scores were 193.9 points higher among those who passed the NGN-PN, compared to those who failed

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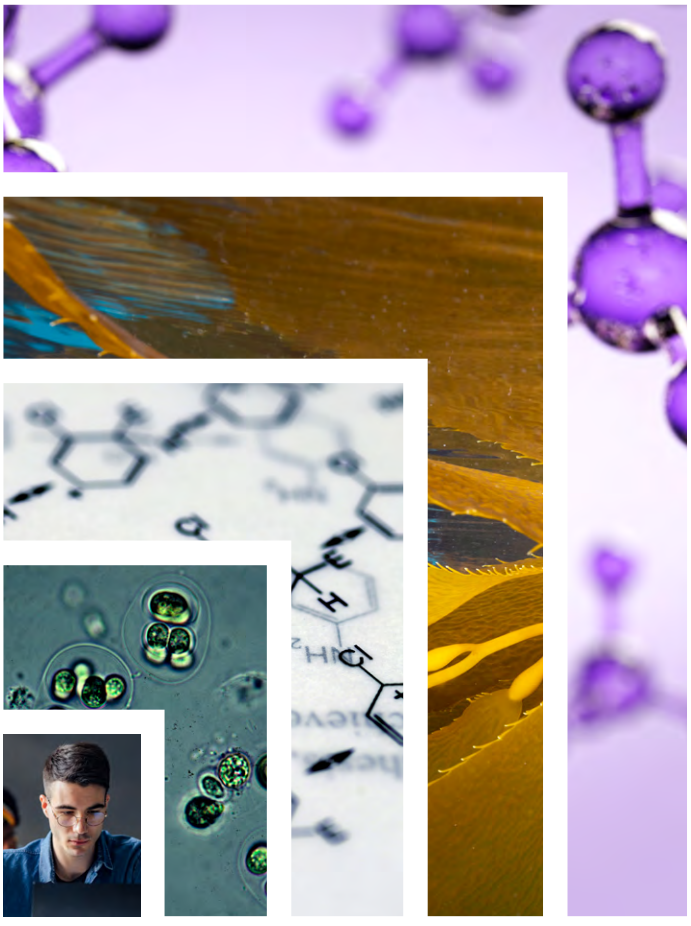
NGN-PN pass rate (based on average E2 score and last E2 score)

Average E2 score	NGN-PN pass rate	Last E2 score	NGN-PN pass rate
≥ 900 benchmark	98.8%	≥ 900 benchmark	98.5%
≥ 850 benchmark	98.7%	≥ 850 benchmark	98.5%
< 850	86.1%	< 850	84.8%

Program policies associated with E2 benchmark attainment

Ten nursing programs provided E2 policy information. The following policies were associated with higher likelihood of achieving benchmark scores, particularly for an average E2 score of ≥850:

- Requiring students to achieve a minimum E2 score
- Requiring multiple attempts if minimum score not achieved
- Allowing three or more exam attempts
- Using HESI Practice Tests
- Reviewing HESI Specialty Exam remediation content
- Implementing Elsevier Adaptive Quizzing (EAQ)
- Providing structured remediation based on student score



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